

STN	Meranie komplexnej permitivity nízkostratových dielektrických podložiek metódou symetrického kruhového diskového rezonátora	STN EN IEC 63185 35 3815
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Measurement of the complex permittivity for low-loss dielectric substrates balanced-type circular disk resonator method

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 05/21

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EUROPEAN STANDARD

EN IEC 63185

NORME EUROPÉENNE

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English Version

**Measurement of the complex permittivity for low-loss dielectric
substrates balanced-type circular disk resonator method
(IEC 63185:2020)**

Méthode au résonateur à disque circulaire de type
symétrique pour mesurer la permittivité complexe des
substrats diélectriques à faible perte
(IEC 63185:2020)

Messung der komplexen Dielektrizitätskonstante für
verlustarme dielektrische Substrate nach dem
symmetrischen Kreisscheibenresonatorverfahren
(IEC 63185:2020)

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CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 63185:2021 (E)**European foreword**

The text of document 46F/523/FDIS, future edition 1 of IEC 63185, prepared by SC 46F "RF and microwave passive components" of IEC/TC 46 "Cables, wires, waveguides, RF connectors, RF and microwave passive components and accessories" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 63185:2021.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2021-10-12
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Annex ZA

(normative)

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<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61338-1-3	1999	Waveguide type dielectric resonators - Part 1-3: General information and test conditions - Measurement method of complex relative permittivity for dielectric resonator materials at microwave frequency	EN 61338-1-3	2000
IEC 62810	2015	Cylindrical cavity method to measure the complex permittivity of low-loss dielectric rods	EN 62810	2015



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INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Measurement of the complex permittivity for low-loss dielectric substrates
balanced-type circular disk resonator method**

**Méthode au résonateur à disque circulaire de type symétrique pour mesurer la
permittivité complexe des substrats diélectriques à faible perte**

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INTERNATIONAL STANDARD

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**MEASUREMENT OF THE COMPLEX PERMITTIVITY
FOR LOW-LOSS DIELECTRIC SUBSTRATES
BALANCED-TYPE CIRCULAR DISK RESONATOR METHOD**

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The text of this International Standard is based on the following documents:

FDIS	Report on voting
46F/523/FDIS	46F/531/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

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MEASUREMENT OF THE COMPLEX PERMITTIVITY FOR LOW-LOSS DIELECTRIC SUBSTRATES BALANCED-TYPE CIRCULAR DISK RESONATOR METHOD

1 Scope

This document relates to a measurement method for complex permittivity of a dielectric substrates at microwave and millimeter-wave frequencies. This method has been developed to evaluate the dielectric properties of low-loss materials used in microwave and millimeter-wave circuits and devices. It uses higher-order modes of a balanced-type circular disk resonator and provides broadband measurements of dielectric substrates by using one resonator, where the effect of excitation holes is taken into account accurately on the basis of the mode-matching analysis.

In comparison with the conventional method described in IEC 62810 and IEC 61338-1-3, this method has the following characteristics:

- the values of the relative permittivity ϵ_r' and loss tangent $\tan\delta$ normal to dielectric plate samples can be measured accurately and non-destructively;
- this method presents broadband measurements by using higher-order modes by one resonator;
- this method is applicable for the measurements on the following condition:
 - frequency: $10 \text{ GHz} \leq f \leq 110 \text{ GHz}$;
 - relative permittivity: $1 \leq \epsilon_r' \leq 10$;
 - loss tangent: $10^{-4} \leq \tan\delta \leq 10^{-2}$.

2 Normative references

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IEC 61338-1-3:1999, *Waveguide type dielectric resonators – Part 1-3: General information and test conditions – Measurement method of complex relative permittivity for dielectric resonator materials at microwave frequency*

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